

## **STW35N60DM2**

# N-channel 600 V, 0.094 Ω typ., 28 A MDmesh™ DM2 Power MOSFET in a TO-247 package

Datasheet - production data

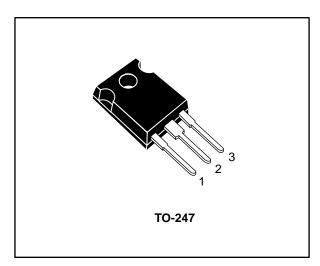
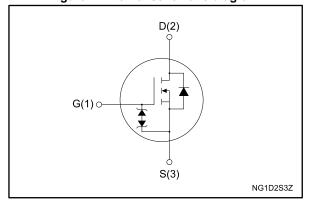


Figure 1: Internal schematic diagram



### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>	P <sub>TOT</sub>
STW35N60DM2	600 V	0.110 Ω	28 A	210 W

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

### **Applications**

Switching applications

## Description

This high voltage N-channel Power MOSFET is part of the MDmesh  $^{\text{TM}}$  DM2 fast recovery diode series. It offers very low recovery charge ( $Q_{\text{rr}}$ ) and time ( $t_{\text{rr}}$ ) combined with low  $R_{\text{DS(on)}}$ , rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

**Table 1: Device summary** 

Order code	Marking	Package	Packing
STW35N60DM2	35N60DM2	TO-247	Tube

Contents STW35N60DM2

## **Contents**

1	Electric	cal ratings	3
		cal characteristics	
	2.1	Electrical characteristics (curves)	6
3	Test cir	·cuits	8
4	Packag	e information	9
	4.1	TO-247 package information	9
5	Revisio	on history	11

STW35N60DM2 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>GS</sub>	Gate-source voltage	±25	V
,	Drain current (continuous) at T <sub>case</sub> = 25 °C	28	۸
I <sub>D</sub>	Drain current (continuous) at T <sub>case</sub> = 100 °C	17	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	112	Α
P <sub>TOT</sub>	Total dissipation at T <sub>case</sub> = 25 °C	210	W
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	50	V/ns
dv/dt <sup>(3)</sup>	dv/dt <sup>(3)</sup> MOSFET dv/dt ruggedness		V/IIS
T <sub>stg</sub>	Storage temperature	-55 to 150	°C
Tj	Operating junction temperature	-55 (0 150	J

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	0.6	900
R <sub>thj-amb</sub>	Thermal resistance junction-amb	50	°C/W

**Table 4: Avalanche characteristics** 

Symbol Parameter		Value	Unit
I <sub>AR</sub>	I <sub>AR</sub> Avalanche current, repetitive or not repetitive		
E <sub>AS</sub> <sup>(1)</sup>	E <sub>AS</sub> <sup>(1)</sup> Single pulse avalanche energy		mJ

#### Notes:

 $<sup>^{\</sup>left(1\right)}$  Pulse width is limited by safe operating area.

 $<sup>^{(2)}</sup>$   $I_{SD} \leq 28$  A, di/dt=900 A/µs;  $V_{DS}$  peak <  $V_{(BR)DSS}, V_{DD}$  = 400 V

 $<sup>^{(3)}</sup>$  V<sub>DS</sub>  $\leq 480$  V.

 $<sup>^{(1)}</sup>$  starting  $T_{j}$  = 25 °C,  $I_{D}$  =  $I_{AR},\,V_{DD}$  = 50 V.

Electrical characteristics STW35N60DM2

### 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			٧
	Zara gata valtaga drain	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			10	
I <sub>DSS</sub> Zero gate current	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V},$ $T_{case} = 125 \text{ °C}$			100	μΑ
I <sub>GSS</sub>	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			±5	μΑ
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 14 A		0.094	0.11	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	2400	ı	
C <sub>oss</sub>	Output capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz, V <sub>GS</sub> = 0 V	-	110	ı	pF
C <sub>rss</sub>	Reverse transfer capacitance		-	2.8	ı	
Coss (1) eq.	Equivalent output capacitance	$V_{DS} = 0$ to 480 V, $V_{GS} = 0$ V	1	190	ı	pF
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> = 0 A		4.3	ı	Ω
$Q_g$	Total gate charge	V <sub>DD</sub> = 480 V, I <sub>D</sub> = 28 A, V <sub>GS</sub> = 10 V (see Figure 15: "Test circuit for gate charge behavior")		54	ı	
$Q_{gs}$	Gate-source charge			14.6	-	nC
$Q_{gd}$	Gate-drain charge	,	-	24.2	-	

#### Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD}$ = 300 V, $I_{D}$ = 14 A R <sub>G</sub> = 4.7 $\Omega$ , $V_{GS}$ = 10 V (see Figure 14: "Test circuit for resistive load switching times" and Figure 19: "Switching time waveform")	-	21.2	-	
t <sub>r</sub>	Rise time		-	17	-	
$t_{\text{d(off)}}$	Turn-off delay time		-	68	1	ns
t <sub>f</sub>	Fall time		-	10.7	-	

 $<sup>^{(1)}</sup>$   $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		1		28	А
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		ı		112	А
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 28 A	ı		1.6	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 28 A, di/dt = 100 A/μs, V <sub>DD</sub> = 60 V (see <i>Figure 16</i> : "Test circuit for inductive	ı	120		ns
Q <sub>rr</sub>	Reverse recovery charge		-	572		nC
I <sub>RRM</sub>	Reverse recovery current	load switching and diode recovery times")		10.2		А
t <sub>rr</sub>	Reverse recovery time		1	215		ns
Q <sub>rr</sub>	Reverse recovery charge	I <sub>SD</sub> = 28 A, di/dt = 100 A/µs, V <sub>DD</sub> = 60 V, T <sub>j</sub> = 150 °C (see <i>Figure 16: "Test circuit for inductive load switching and diode</i>	-	1.89		μC
I <sub>RRM</sub>	Reverse recovery current	recovery times")		17.7		А

#### Notes:

**Table 9: Gate-source Zener diode** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 250 \mu\text{A},  I_{D} = 0 \text{A}$	±30	ı	ı	V

The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

<sup>&</sup>lt;sup>(1)</sup> Pulse width is limited by safe operating area.

 $<sup>^{(2)}</sup>$  Pulse test: pulse duration = 300  $\mu$ s, duty cycle 1.5%.

## 2.2 Electrical characteristics (curves)

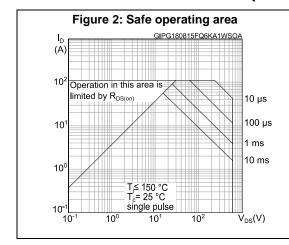
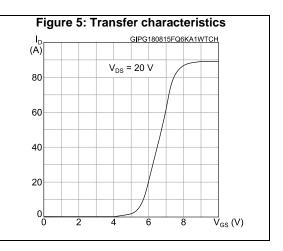
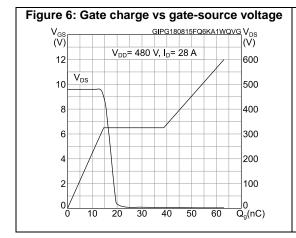
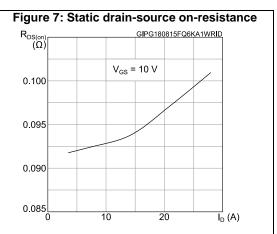


Figure 3: Thermal impedance K  $\delta = 0.5$   $\delta = 0.2$   $\delta = 0.05$   $\delta = 0.01$   $\delta = 0.01$ Single pulse  $\delta = t_p/T$   $\delta = t_p$ 







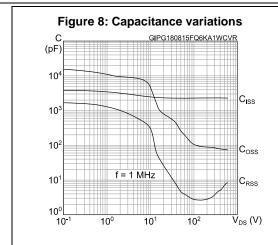
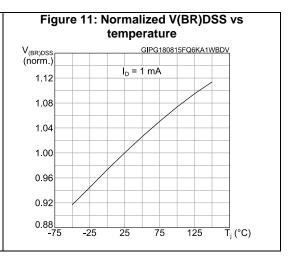


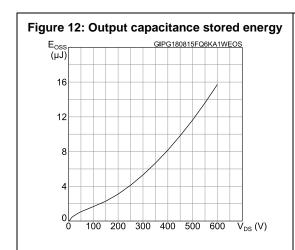
Figure 10: Normalized on-resistance vs temperature

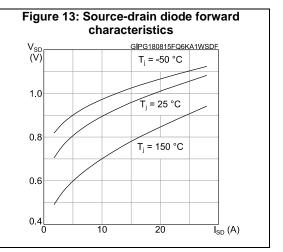
R<sub>DS(on)</sub> GIPG180815FQ6KA1WRON

2.2 V<sub>GS</sub> = 10 V

1.8 1.4 1.0 0.6 0.2 T<sub>j</sub> (°C)







**Test circuits** STW35N60DM2

#### 3 **Test circuits**

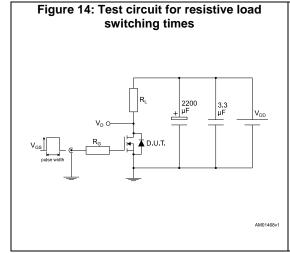


Figure 15: Test circuit for gate charge behavior 1 kΩ ⊥ 100 nF I<sub>G</sub>= CONST 2.7 kΩ 47 kΩ

Figure 16: Test circuit for inductive load switching and diode recovery times

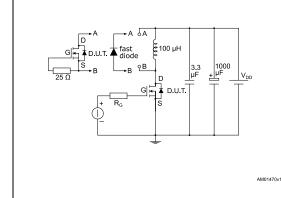


Figure 17: Unclamped inductive load test circuit

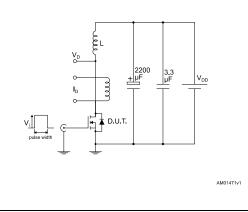


Figure 18: Unclamped inductive waveform

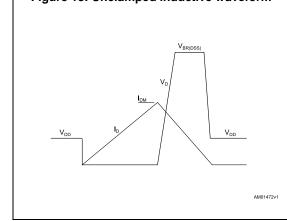
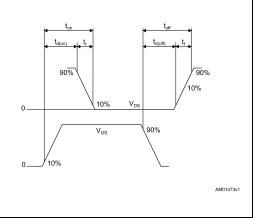


Figure 19: Switching time waveform



## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

## 4.1 TO-247 package information

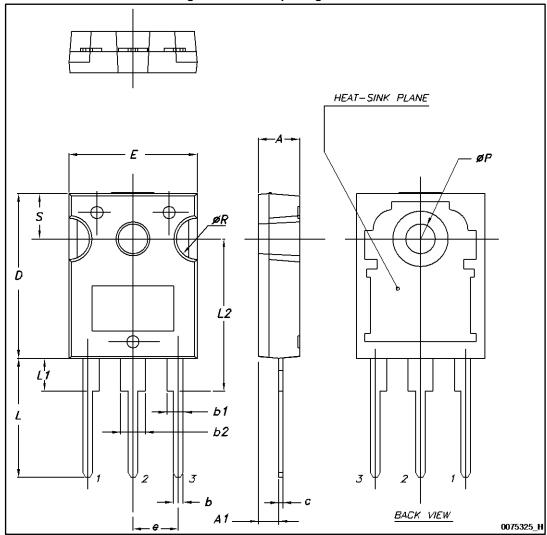


Figure 20: TO-247 package outline

Table 10: TO-247 package mechanical data

Dim	mm.				
Dim.	Min.	Тур.	Max.		
А	4.85		5.15		
A1	2.20		2.60		
b	1.0		1.40		
b1	2.0		2.40		
b2	3.0		3.40		
С	0.40		0.80		
D	19.85		20.15		
Е	15.45		15.75		
е	5.30	5.45	5.60		
L	14.20		14.80		
L1	3.70		4.30		
L2		18.50			
ØP	3.55		3.65		
ØR	4.50		5.50		
S	5.30	5.50	5.70		

STW35N60DM2 Revision history

# 5 Revision history

Table 11: Document revision history

Date	Revision	Changes
02-Sep-2015	1	Initial version

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